

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10562458	BREDERLOW ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	JOHN F MORTELL	4154

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
340	572.100	3/10/2008	/JM/
327	176	3/13/2008	/JM/

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
PALM Inventor Name Search	3/10/2008	/JM/
EAST Search Notes Included	3/5-3/13/2008	/JM/
NPL: ACM Digital Library: AC RFID tag	3/19/2008	/JM/
Confer with Benjamin Lee, Supervisory Patent Examiner	5/4/2009	/JM/
EAST: update search; search notes included.	5/11/2009	/JM/
Confer with Daniel Wu, Supervisory Patent Examiner	11/19/2009	/JM/
EAST: update search; search notes included.	11/19, 12/2/2009	/JM/
Confer with Daniel Wu, Supervisory Patent Examiner	5/14/2010	/JM/
EAST: update search; search notes included.	5/19-20/2010	/JM/

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
340	572.1	5/20/2010	/JM/
327	176	5/20/2010	/JM/

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